



INTELLECTUAL PROPERTY  
402-391-4448

JAMES D. WELCH  
ATTORNEY AT LAW  
PROFESSIONAL ENGINEER

June 14, 2003

Commissioner for Patents  
BOX: 1450  
Alexandria, VA 22313-1450

RE: PUBLISHED APPLICATION OF KWON TITLED: "METHODS AND APPARATUS  
FOR DETERMINING OPTICAL CONSTANTS OF SEMICONDUCTORS AND  
DIELECTRICS WITH INTERBAND STATES";  
PUB. NO. US2003/0073254A1;  
PUB. DATE: APR. 17, 2003;  
APPL. NO. 09/363,638

OPPOSITION

Dear Sir;

Accompanying herewith is a check for \$180.00, a Listing of,  
and copies of materials we feel should be considered in the  
examination of the identified Patent Application.

LISTING

- DO Patent No. 4,332,833, Serial No. 126,217, Issued Jun. 1, 1982 to  
Aspnos et al.
- DO Patent No. 6,362,881 B1 to Pickering et al., Serial No.  
09/297,819, Issued Mar. 26, 2002.
- DO "Modeling the Optical Dielectric Function of Semiconductors:  
Extension of the Critical-Point Parabolic-Band Approximation";  
Kim, Physical Rev. B, Vol. 45, No. 20, (May 1992).
- DO "Parameterization of the Optical Functions of Amorphous Materials  
in the Interband Region", Jellison et al., Appl. Phys. Lett.  
69(3) (July 1996).
- DO "Optical Dispersion Relations for Amorphous Semiconductor and  
Amorphous Dielectrics", Forouhi & Bloomer, Phys. Rev. B, Vol. 34,  
No. 10, (Nov. 1986).
- DO "Optical Dispersion Relations for Si and Ge", Adachi, J. App.  
Phys. 66(7), (Oct. 1989).
- DO From Optical Metrology, "Overview of Variable Angle Spectroscopic  
Ellipsometry (VASE), Part II, Johs et al., Soc. Photo-Opt.  
Instrum. Eng. (1999).

EXAMINER:

*Don George*

3/2/04 - DATE CONSIDERED

10320 PINEHURST AVE  
OMAHA, NEBRASKA 68154

RECEIVED  
JUN 19 2003  
TECHNOLOGY CENTER 2800



"Optical Properties of Bulk and Thin-Film Sr-TiO<sub>2</sub> on Si and PT",  
Zollner et al., J. Vac. Sci. Technol. B 19(4) (2000).

From Wiley Encyclopedia of Electrical and Electronics  
Engineering---Supplement 1, Editor Webster, John Wiley & Sons,  
(2000).

"Development of a Parametric Optical Constant Model for  
Hg<sub>10</sub>Cd<sub>90</sub>Te for Control of Composition by Spectroscopic  
Ellipsometry During MBE Growth", Johs et al., Thin Solid Films,  
313-314 (1998).

Service was made on the Applicant's Attorney, Antonelli  
Terry Stout and Kraus at Suite 1800, 1300 North Seventeenth  
Street, Arlington, VA 22209, via First Class Mail sent on  
June 14, 2003

Sincerely,

JAMES D. WELCH  
JW/hs  
enc.

EXAMINER: *David J. [Signature]*

DATE RECORDED: 3/2/04

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 178.39931X00	SERIAL NO. 09/963638
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use several sheets if necessary)		APPLICANT Daewon KWON	
		FILING DATE September 27, 2001	GROUP

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
120	AA	6,049,220	04/11/00	Borden et al.		06/10/98
120	AB	5,883,518	03/16/99	Borden		04/24/96
120	AC	4,854,710	08/08/89	Opsal et al.		07/23/87
120	AD	5,966,019	10/12/99	Borden		04/24/96
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
	AN						
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

120	AU	Tauc et al., "Optical Properties and Electronic Structure of Amorphous Germanium", <i>Phys. Stat. Sol.</i> 15, 627 (1966), pp. 627-637.				
120	AV	J. Bourgoin et al., <i>Point Defects in Semiconductors II</i> , Springer-Verlag, Berlin, Heidelberg, New York 1983.				
	AW					
	AX					
	AY					
	AZ					
Examiner <i>Daewon Kwon</i>				Date Considered 3/2/04		